Best Paper Award

Each year, VLSI Test Symposium presents an award to the authors of the most outstanding paper. The VTS Awards Selection Committee considers the quality of all of the papers as published in the digest of papers and as presented in the technical sessions. The committee’s decision is based on the responses given on the session rating cards submitted by symposium attendees, reviewer’s comments, and on the recommendations of the VTS Program Committee.

The paper selected by the VTS Awards Selection Committee as the most outstanding paper in 1994 is, “Structural Constraints for Circular Self-Test Paths,” by Joan Carletta and Christos Papachristou of Case Western Reserve University. This paper is reprinted in the 1995 digest of papers beginning on page 486.

In their paper, the authors describe circuit constraints required to avoid bit-level correlation, which can significantly degrade fault coverage in designs using the circular Built-In Self-Test technique.

Congratulations to the winners!